

Substitute for form 1449A/PTO

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

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Complete if Known

Application Number	10/081,818
Filing Date	February 20, 2002
First Named Inventor	Eldridge, Jerome
Group Art Unit	2818
Examiner Name	Ho, Tu-Tu

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Attorney Docket No: 1303.045US1

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**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

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	Filing Date	February 20, 2002
	First Named Inventor	Eldridge, Jerome
	Group Art Unit	2818
	Examiner Name	Ho, Tu-Tu
Sheet 7 of 8		Attorney Docket No: 1303.045US1

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